Effect of Indentation on *I-V* Characteristics of Au/n-GaAs Schottky Barrier Diodes

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Au/n-GaAs Schottky barrier diodes (SBDs) have been fabricated. The effect of indentation on Schottky diode parameters such as Schottky barrier height (ϕ_b) and ideality factor (n) was studied by current-voltage (I-V) measurements. The method used for indentation was the Vickers microhardness test at room temperature. The experimental results showed that the I-V characteristics move to lower currents due to an increase of ϕ_b with increasing indentation weight, while contacts showed a nonideal diode behaviour.

Key words: Schottky Barrier Diode; Barrier Height; Ideality Factor; Indentation; Fermi Level Pinning.